Abstracts

W-band on-wafer load-pull measurement system and its application to HEMT characterization

E. Alekseev, D. Pavlidis and C. Tsironis. "W-band on-wafer load-pull measurement system and its application to HEMT characterization." 1998 MTT-S International Microwave Symposium Digest 98.3 (1998 Vol. III [MWSYM]): 1479-1482.

An on-wafer large-signal characterization system has been developed for W-band frequency applications. The system is computer-controlled and employs a high-precision electromechanical W-band tuner. Its application to obtaining constant output power and gain contours as well as power saturation characteristics of submicron InP-based HEMTs is demonstrated at 77 GHz and 102 GHz.

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